

# Practical Considerations in Quantitative Dark and Illuminated Lock-In Thermography Analyses of Shunts in Silicon Thin-Film Modules

Felice Friedrich<sup>1,\*</sup>, Karolina Mack<sup>1</sup>, Nandha Krishnan<sup>1</sup>, Sven Kühnapfel<sup>1,2</sup>, Bernd Stannowski<sup>2</sup>, Christof Schultz<sup>3</sup>, Rutger Schlatmann<sup>2,3</sup>, and Christian Boit<sup>1</sup>  
<sup>1</sup>PVcomb/Technische Universität Berlin, Germany; <sup>2</sup>PVcomb/Helmholtz-Zentrum Berlin für Materialien und Energie GmbH, Berlin, Germany; <sup>3</sup>PVcomb/University of Applied Sciences (HTW) Berlin, Germany  
 \*Corresponding author: felice.friedrich@pvcomb.de

## Motivation

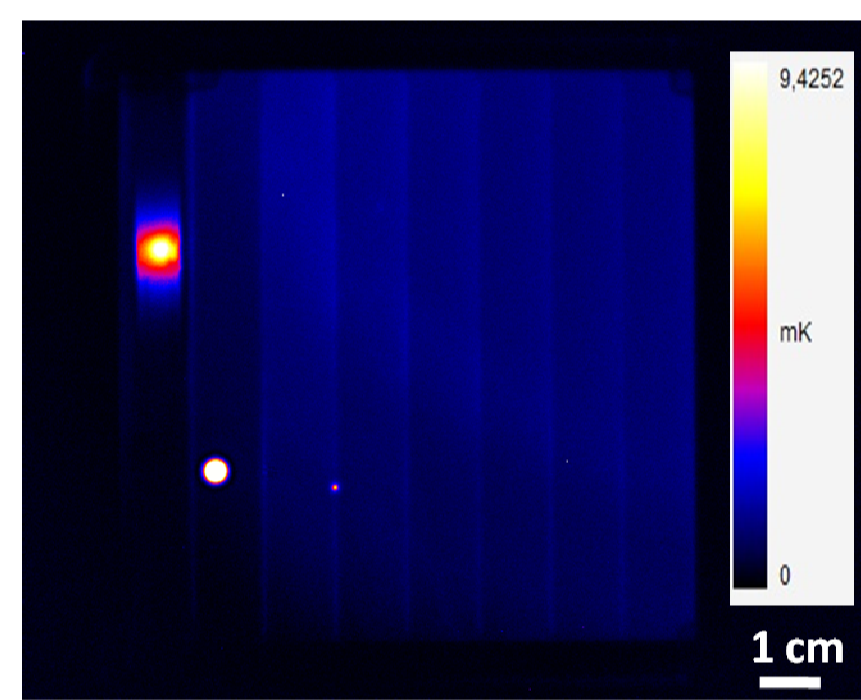
- Hot spots in photovoltaic modules deteriorate the performance and may finally cause breakdown, even fire.
- Method of choice for localization of hot spots/shunts in solar cells: Lock-In Thermography (LIT).
- Technological progress has reduced cost and time.
- Scientific research now focuses on an extension to quantitative analyses e.g. for shunt removal classification.

## LIT Experimental Results

### DLIT close to MPP

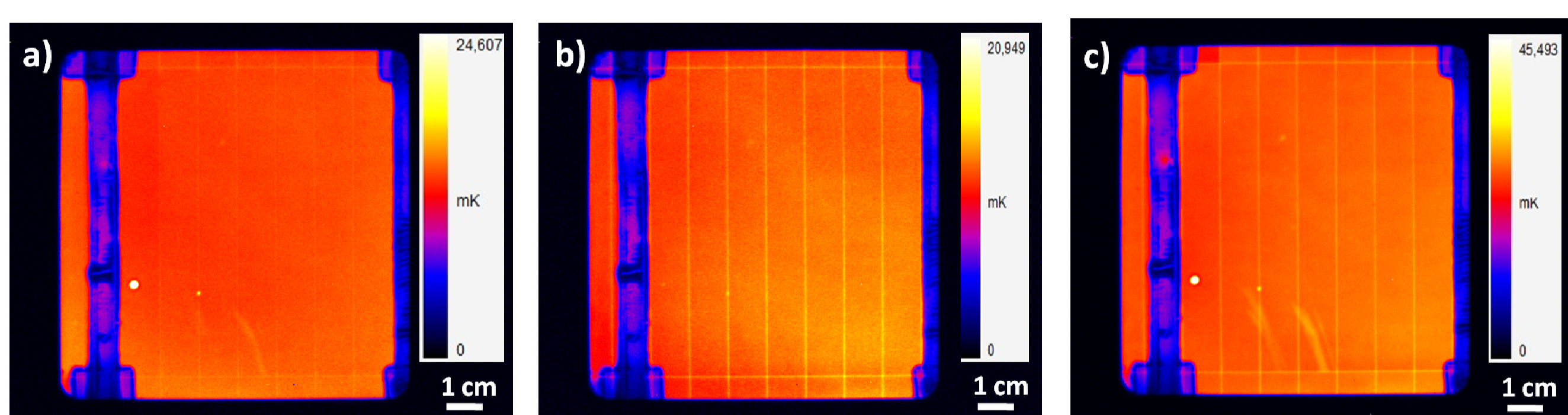
$V = 10\text{ V}$ ,  $I = 5.2\text{ mA}$ ,  $f_{\text{Lock-In}} = 0.5\text{ Hz}$ ,  $t = 1\text{ min}$

- 3 visible shunts:
  - in cell 1 below the copper band (broadened)
  - in cell 2 in the material
  - laser scribe between cell 2&3
- Demonstrates excellent homogeneity of the material (apart from shunts, copper and isolation tape)
- Shunts not visible in thermograph taken at reverse bias ( $V = -10\text{ V}$ )



### $V_{\text{oc}}$ -ILIT

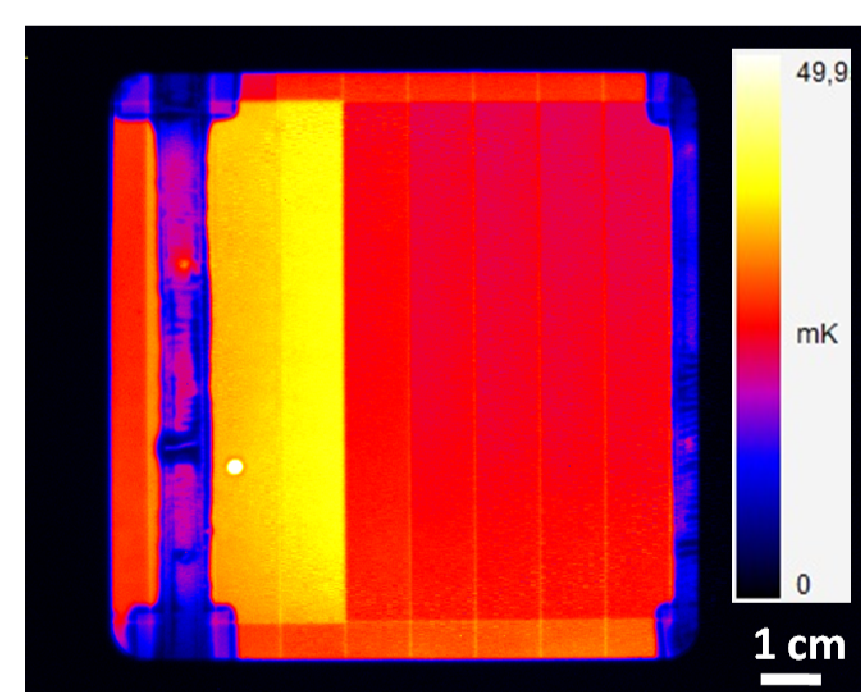
- No current flow, taken at different wavelength
  - a) green for selective excitation of a-Si:H subcell
  - b) red for selective excitation of  $\mu\text{c-Si:H}$  subcell
  - c) red&green at similar intensity for general optic excitation



- Shunt in cell 2 does not show under red illumination
- Interconnection shunt is reduced under red illumination
- Non-contacted regions at top&bottom show up with similar  $\Delta T$

### $J_{\text{sc}}$ -ILIT

- Full photocurrent current is allowed to flow
- Cells 1-3 show higher temperature (relates to  $R_s$ )
- Cells 5-8 show lower average temperature than non-contacted regions at top&bottom



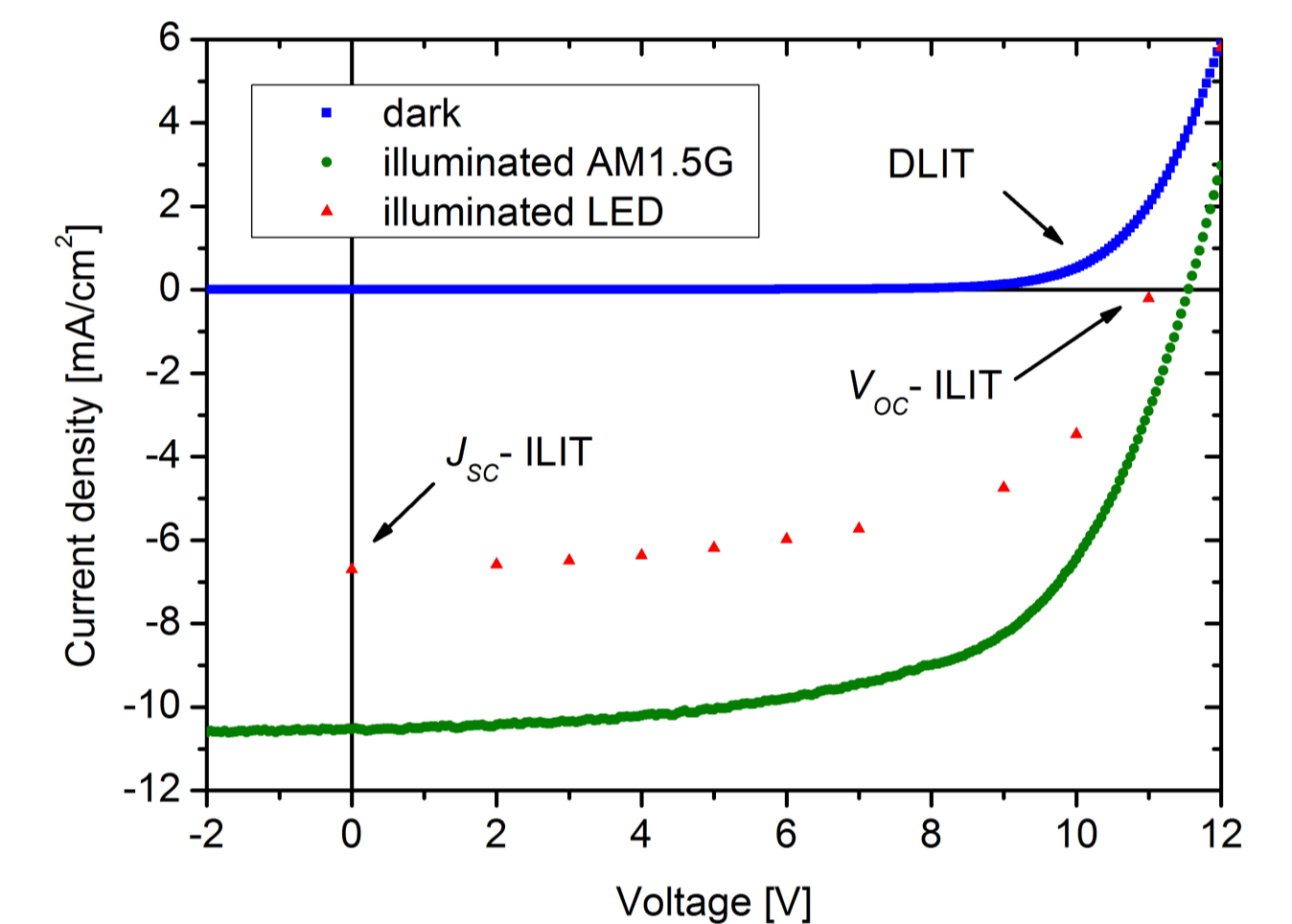
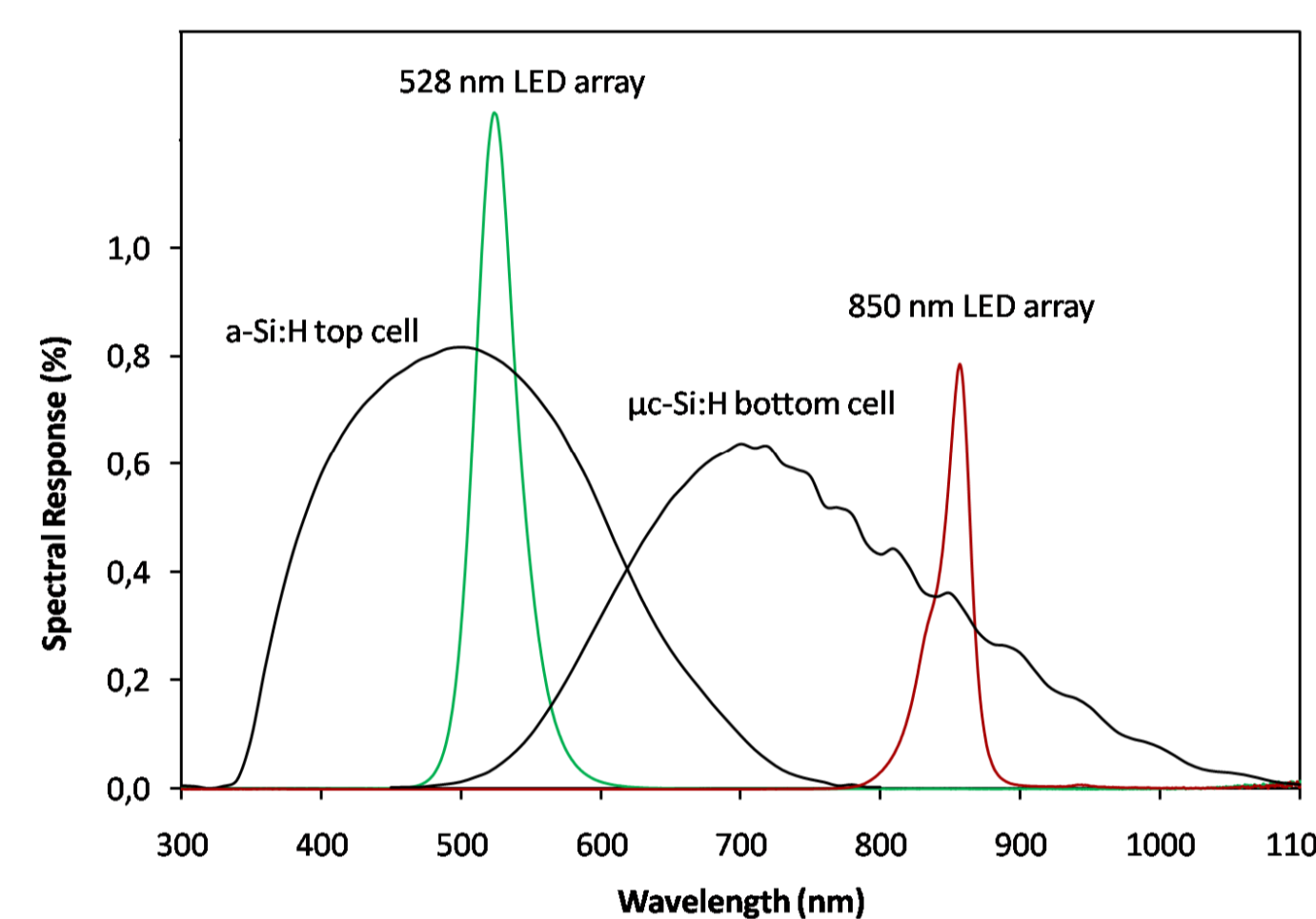
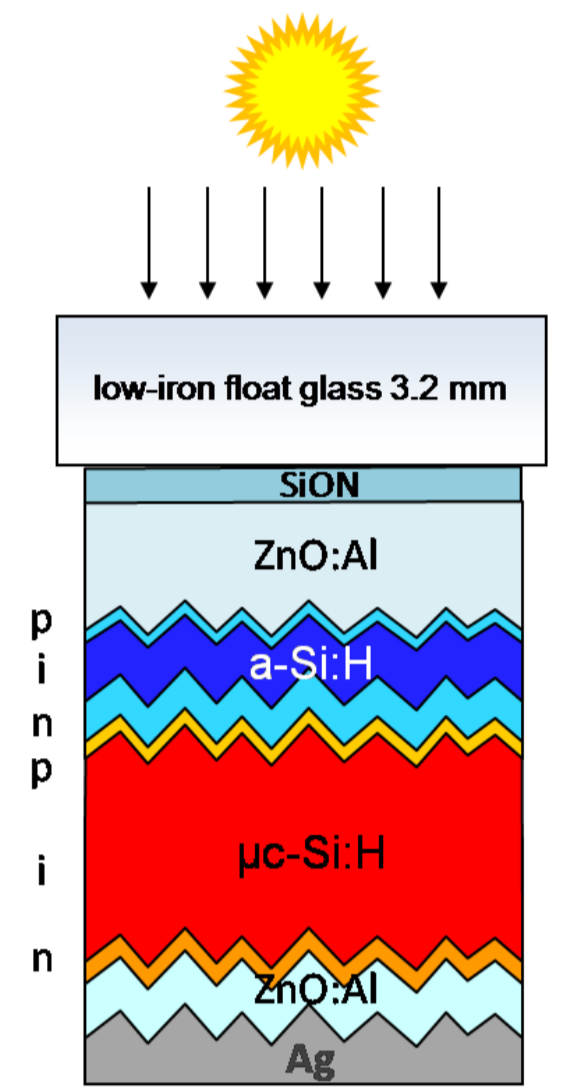
## Experimental Details

### Samples

- State-of-the-art a-Si:H/ $\mu\text{c-Si:H}$  tandem minimodules [1]
- Total area of  $8 \times 8\text{ cm}^2$  on  $10 \times 10\text{ cm}^2$  glass substrate
- in this study: containing shunts

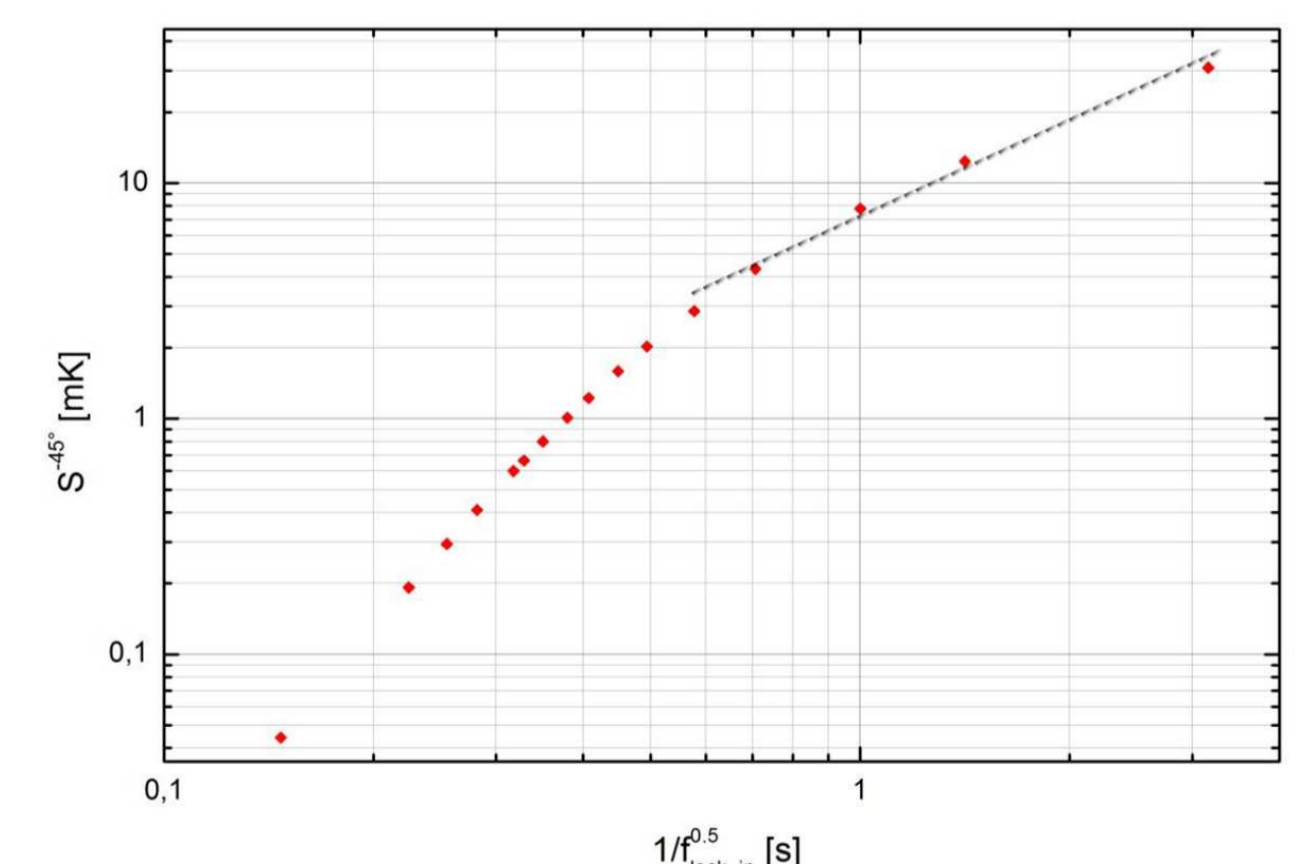
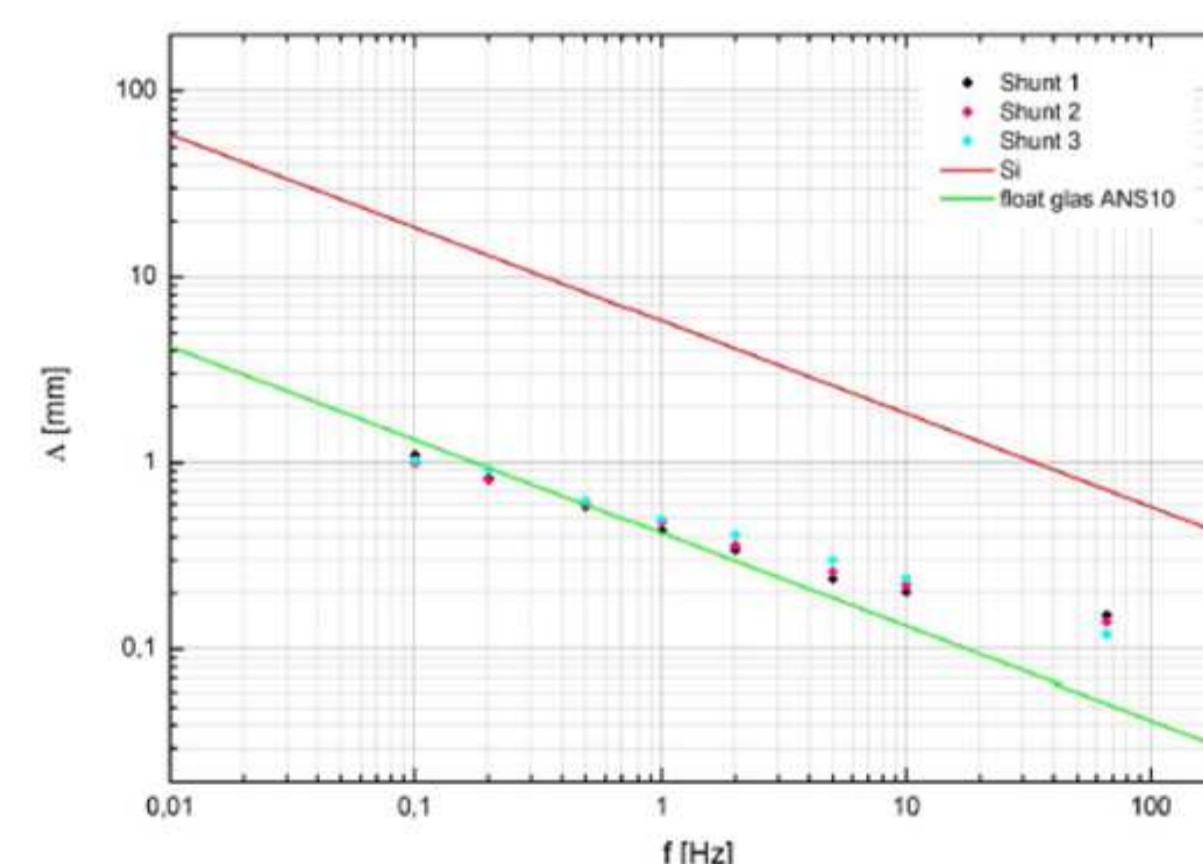
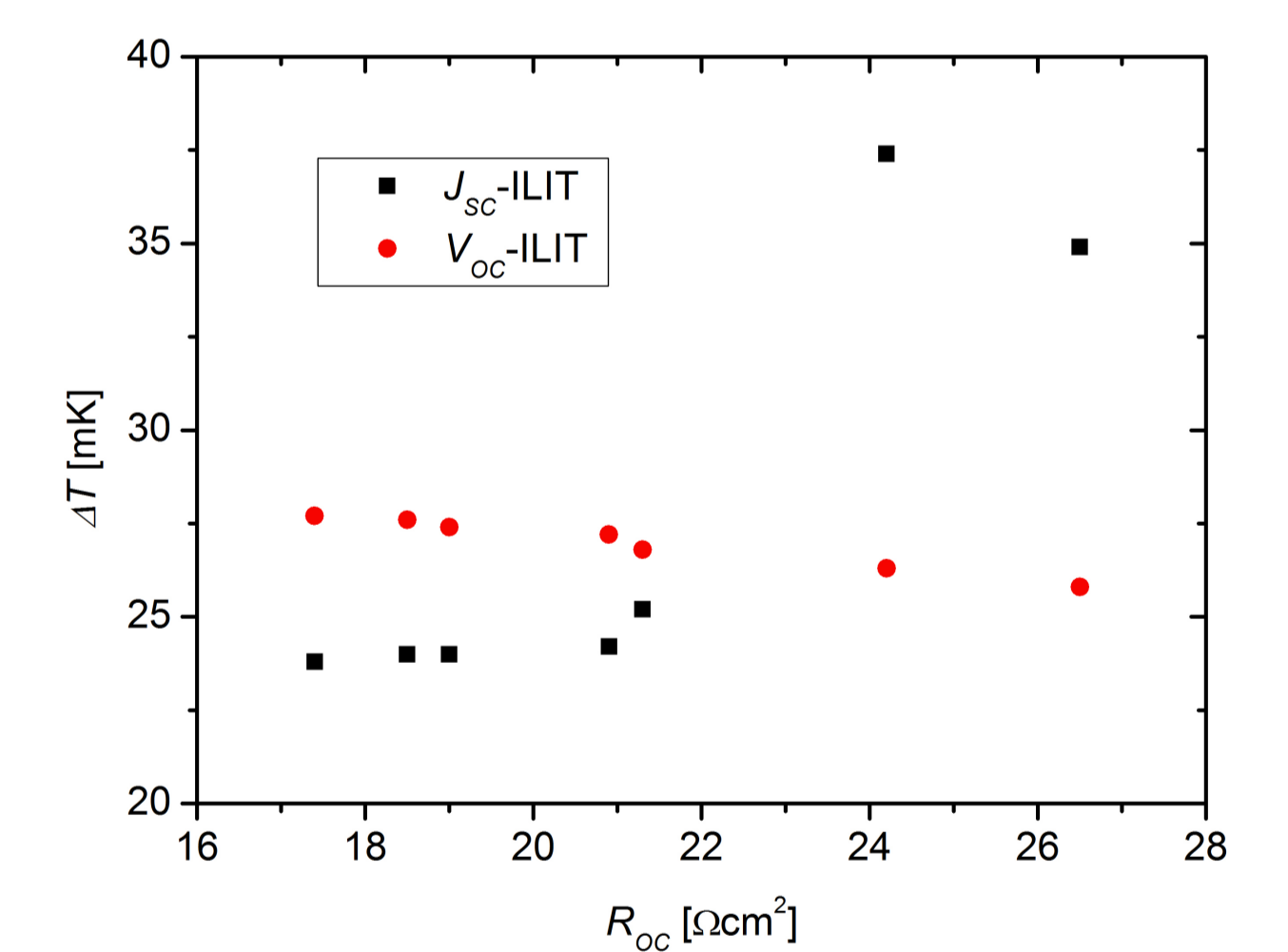
### LIT setup

- Pulsed electric and optic excitation for application of DLIT and ILIT methods on solar cells and modules
- Red and green LED arrays for selective excitation of tandem cell layers [2] with  $30 \times 30\text{ cm}^2$  uniform illumination ( $360\text{ W/m}^2$ )
- Contacting via copper stripes, black adhesive foil for homogeneous emissivity



## Discussion: Shunts and Quantitative Analysis

- Non-ohmic shunt in cell 2 is localized in the amorphous subcell (amounts to  $\sim 1\%$  of  $I_{\text{cell}}$  based on image integration method [3])
- Series resistance correlates with temperature increase in  $J_{\text{sc}}$ -ILIT mode due to Joule heating
- Thermalization effect is observed in non-contacted regions in  $V_{\text{oc}}$ -ILIT mode
- Peltier effect is observed in  $J_{\text{sc}}$ -ILIT due to heat transport by the lateral current
- Additional effects hindering quantitative analysis of shunts in LIT:
  - influence of glass substrate and layered sample structure on thermal diffusion length
  - influence of the emissivity foil on the signal phase shift



## Conclusions

- Quantitative analysis of shunts in Si thin-film solar cells is feasible for DLIT under consideration of the correct measurement range.
- Illuminated LIT signal contains more information (like thermalization and Peltier) that nevertheless hinder a straightforward shunt analysis and call for support via thermo-opto-electronic device simulation.

## References

- [1] B. Rau et al., *Photovoltaics International*, 17 (2012) 99
- [2] H. Straube et al., *physica status solidi (c)*, 8 (2011) 1339
- [3] Breitenstein, Warta, and Langenkamp (2010) Springer